

<b>Notice of References Cited</b>	Application/Control No. 10/005,594	Applicant(s)/Patent Under Reexamination AYER ET AL.	
	Examiner Simon J. Oh	Art Unit 1615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,252,338	10-1993	Jao, Frank et al.	
	B	US-6,096,339	08-2000	Ayer, Atul D. et al.	
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

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